# 2SC5954

## Silicon NPN triple diffusion planar type

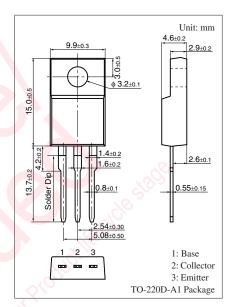
For power amplification with high forward current transfer ratio

#### ■ Features

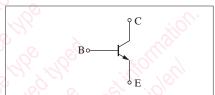
- High forward current transfer ratio h<sub>FE</sub> which has satisfactory linearity.
- ullet Low collector-emitter saturation voltage  $V_{CE(sat)}$
- Full-pack package which can be installed to the heat sink with one screw.

### ■ Absolute Maximum Ratings $T_C = 25$ °C

| Parameter                             | Symbol           | Rating      | Unit |  |
|---------------------------------------|------------------|-------------|------|--|
| Collector-base voltage (Emitter open) | $V_{CBO}$        | 80          | V    |  |
| Collector-emitter voltage (Base open) | V <sub>CEO</sub> | 60          | V    |  |
| Emitter-base voltage (Collector open) | $V_{EBO}$        | 6           | V    |  |
| Collector current                     | $I_{C}$          | 3           | A    |  |
| Peak collector current                | $I_{CP}$         | 6           | A    |  |
| Collector power dissipation           | P <sub>C</sub>   | 25          | W    |  |
| $T_a = 25$ °C                         |                  | 2.0         |      |  |
| Junction temperature                  | Tj               | 150         | °C   |  |
| Storage temperature                   | $T_{stg}$        | -55 to +150 | °C   |  |
|                                       |                  |             |      |  |



#### Internal Connection



### ■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

| Parameter                                    | Symbol               | Conditions   | Min | Тур | Max  | Unit |
|--|----------------------|--|-----|-----|------|------|
| Collector-emitter voltage (Base open)        | $V_{CEO}$            | $I_C = 10 \text{ mA}, I_B = 0$                                     | 60  |     |      | V    |
| Collector-base cutoff current (Emitter open) | $I_{CBO}$            | $V_{CB} = 80 \text{ V}, I_{E} = 0$                                 |     |     | 100  | μΑ   |
| Collector-emitter cutoff current (Base open) | I <sub>CEO</sub>     | $V_{CE} = 40 \text{ V}, I_{B} = 0$                                 |     |     | 100  | μΑ   |
| Emitter-base cutoff current (Collector open) | $I_{EBO}$            | $V_{EB} = 6 \text{ V}, I_C = 0$                                    |     |     | 100  | μΑ   |
| Forward current transfer ratio               | h <sub>FE1</sub> *   | $V_{CE} = 4 \text{ V}, I_{C} = 0.5 \text{ A}$                      | 500 |     | 2300 | _    |
|  | h <sub>FE2</sub>     | $V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$                        | 100 |     |      |      |
| Collector-emitter saturation voltage         | V <sub>CE(sat)</sub> | $I_C = 1 \text{ A}, I_B = 20 \text{ mA}$                           |     |     | 0.6  | V    |
| Transition frequency                         | $f_T$                | $V_{CE} = 10 \text{ V}, I_{C} = 0.1 \text{ A}, f = 10 \text{ MHz}$ |     | 200 |      | MHz  |
| Turn-on time                                 | t <sub>on</sub>      | I <sub>C</sub> = 1 A, Resistance loaded                            |     | 0.2 |      | μs   |
| Storage time                                 | t <sub>stg</sub>     | $I_{B1} = 0.1 \text{ A}, I_{B2} = -0.1 \text{ A}$                  |     | 1.5 |      | μs   |
| Fall time                                    | $t_{\rm f}$          | $V_{CC} = 50 \text{ V}$  |     | 0.1 |      | μs   |

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

#### 2. \*: Rank classification

| Rank             | Q           | Р              |
|------------------|-------------|----------------|
| h <sub>FE1</sub> | 500 to 1500 | 1 300 to 2 300 |

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